

Quantitative Analysis

Reference Intensity Ratio (RIR)



Reference Intensity Ratio (RIR) What is it?

The Reference Intensity Ratio (RIR) is a method used for Quantitative Analysis by Powder Diffraction.

The RIR method is based upon scaling all diffraction data to the diffraction of standard reference materials.



Reference Intensity Ratio (RIR) Why?

The intensity of a diffraction peak profile is a convolution of many factors, only one of which is the concentration of the analyte (species being measured).

By using the RIR method, ratios scaled to a common reference, are used in the experiment. The assumption is that all the factors, *except concentration*, of the analyte are ratioed and reduced to a constant.

By using ratios and measuring peak areas, the RIR method can be used to determine concentrations.



Reference Intensity Ratio (RIR) How ?

The RIR method scales all diffraction data to a standard. By convention, corundum is used as the international reference and the scale factor is defined by:

Intensity Analyte / Intensity Corundum = I / Ic

I/Ic can be experimentally derived by adding a known weight fraction of corundum to a pure specimen of the analyte of interest.

I/Ic can also be calculated if the atomic parameters of analyte are known because the atomic parameters of corundum have been determined.

In PDF-4+, I/Ic has been experimentally determined for close to 10,000 materials and has been calculated for >170,000 materials.



Overview of the Method

To understand how to use I/Ic values for quantitative analysis with the PDF-4+ database, a short description of the method is provided in the following slides.





Reference Intensity Ratio (RIR) What?

RIR Method

- RIR, as used in the Powder Diffraction File, is I/Ic (reference to corundum).
- I/Ic can be determined, experimentally or calculated, from a crystal structure, both methods are used in the PDF-4+ database.
- Experimentally, I/Ic can be determined by taking the ratio of the strongest line of the pattern to the intensity of the strongest line of corundum in a 50/50 weight mixture.
- If we know the crystal structure, we can calculate I/Ic as shown in the following slide.



Reference Intensity Ratio (RIR)

RIR Method All calculated patterns have I/Ic.

$$I/Ic = \mu \gamma \rho c / \mu c \gamma c \rho$$

μ = Linear attenuation coefficient
γ = Absolute scale factor
ρ = Density
(Subscript "c" corresponds to corundum)

Single crystal determinations have all the data necessary to calculate the variables in the above equation from atomic parameters and the unit cell parameters with the use of atomic scattering factors and published constants. These are used by the ICDD to calculate I/Ic for these entries.



Reference Intensity Ratio (RIR)

RIR Method Calculated I/Ic values often significantly differ from experimental I/Ic values.

Natural products, minerals, and biomaterials often contain trace impurities, anion/cation substitution in the lattice, or naturally produced vacancies, and/or defects in the crystalline state. These physical phenomena are well known to influence peak intensities and peak profiles that will change the I/c value. This value can be significantly different from one calculated from a perfect crystalline pure material.

If you are using I/Ic to quantitate a synthetic mixture, you may want to use a calculated value. If you are using I/Ic to quantitate a natural product or mineral sample, you may prefer experimental values.



Quantitative Analysis

Main equation for quantitative analysis K_{ia} contains structure factor, multiplicity, Lorentz-polarization factor, temperature factor + scale factor for reflection i of phase a I_{ia} = intensity of $X_a = wt$ fraction of reflection i of phase a (want this!!) ia = phase a ρ_aμ μ = Linear attenuation coefficient ρ_a is density of phase a



Quantitative Analysis







Quantitative Analysis Reference Intensity Ratios



For 50-50 mixture of analyte with corundum $\frac{I_a}{I_c} = K \dots denoted (I/I_c)_a$

RIR Method



Quantitative Analysis Reference Intensity Ratios

$$\frac{\mathbf{I}_{a}}{\mathbf{I}_{c}} = \frac{\mathbf{K}_{a}\mathbf{X}_{a}\rho_{c}}{\mathbf{K}_{c}\mathbf{X}_{c}\rho_{a}} = \mathbf{K}\frac{\mathbf{X}_{a}}{\mathbf{X}_{c}}$$

For any a + b mixture

 $\begin{pmatrix}
I_{a}/I_{c})\\
(I_{b}/I_{c})
\end{pmatrix} = \frac{\begin{matrix}
K_{a}\rho_{c}\\
V_{c}\rho_{a}\\
\hline
K_{b}\rho_{b}\end{matrix}}{\begin{matrix}
K_{a}\\
\hline
V_{c}\rho_{b}\\
\hline
K_{a}\\
\hline
\hline
K_{a}\\
\hline
K_{b}\\
\hline
\rho_{b}\rho_{b}\end{matrix}} = \frac{\begin{matrix}
(I/I_{c})_{a}\\
\hline
X_{a}\\
\hline
(I/I_{c})_{b}\\
\hline
X_{b}\\
\hline
\end{matrix}$



Reference Intensity Ratio (RIR) Practical Considerations

RIR Method The RIR method uses simultaneous equations to solve analyte concentrations in a multicomponent mixture.

Many vendor programs interface to PDF-4+ to automatically extract I/Ic and peak areas from the experimental data for automated quantitative analysis.

Automated programs assume that the combination of all phases identified account for all observed scattering and 100% of the specimen. Significant errors can occur, if there are non-crystalline phases or unidentified materials present in the specimen.



Finding I/Ic Search





1) 2) 3)

Finding I/Ic for a Material

	DD DDView+ - P	DF-4+ 2007 RDB					
File I	Edit Tools Wind	ow Help		-			
							References
I Re	esults - {Empiri	cal Formula Contain					
File	Edit Field Res	ults Indexing Help	- M				General Search PDF Card Diffraction SIeve+ Electron
		24					Field Sets
Res	ults (200 272,23	2)	a sector se				ICDD Defaults 🛛 🖓 📫 Add Rename 💥 Delete
Sea	arch Preference Set	ICDD Defaults	,				Available Fields
		Chaminal Exercicle	Conserved Name	D1	D2 D2	eve	L2 PDF #
00-0	001-0562 B		Titanium Oxide	3 520000 13	880000 1 70000	0 T	
00-0	001-1292 B	Ti O2	Titanium Oxide	1.690000 3.3	240000 2.49000	0 T	Dcalc Chemical Formula
00-0	002-0387 B	Ti O2	Titanium Oxide	3.510000 1.3	890000 1.70000	0 T	Diffusion Diffus
00-0	002-0406 O	Ti O2	Titanium Oxide	3.470000 1.0	880000 1.69000	0 T	I/Ic D2
00-0	002-0494 O	TI 02	Titanium Oxide	3.240000 1.	680000 1.36000	0 T	Melting Point D3
00-0	002-0514 0	Ti 02	Titanium Oxide	3.220000 1.	680000 2.45000	0 0	MP Low SYS
00-0	003-0380 B	11.02	Titanium Oxide	1 690000 2.3	250000 1.88000		MP High
00-0	004-0477 1	TI 02	Titanium Oxide	3.510000 1.	891000 2.37900	0 T	Color
00-0	004-0551	Ti O2	Titanium Oxide	3.245000 1.	687000 2.48900	0 T	
00-0	015-0875 S	Ti O2	Titanium Oxide	3.512000 2.5	900000 3.46500	0 0	Prompt for report title
00-0	016-0617 S	Ti O2	Titanium Oxide	3.512000 2.5	900000 3.46500	0 0	Scale report fields to page
e Sel Sel	rfori lect lect	m a Sea the Pre I/Ic to d	arch ference lisplay V	s T ′alu	āb Jes	о Т Т О О Н Т М М М О О О О О О О О О О О О О	OK Cancel Reset Page Reset All Apply
-Sea {Em	rch Description pirical Formula Con	tains Elements 'Ti' And 'O2'} And {Number	of Elements (2)}				Calculations Mean: Median: ESD:
	C Search	Results - (Empirical Form			T and		
	start 🦉 🚺	🔰 📿 🧐 🧭 🧉 👯 ICDD DD\	/iew+ 😼 My Computer 🛛 🔮	₩ Ê:\	G M	icrosoft Powe	r 🦉 untitled - Paint 💦 🧭 📔 🍕 🖅 🔂 🐺 🏷 🦳 🍪 🏷 😓 💭 8:23 AM



Finding I/Ic for a Material

File Edit Fields Results Indexing Help													
Results (206 of 272,232)													
Search Preference Sel	: ICDD Defaul												
PDF# QM	Chemical F	Compound Name	SYS	I/Ic	D1	D2	D3						
01-072-4814 I	TI O2	Titanium Oxide	Т	3.5	3.251060	1.688030	2.486680						
01-072-4815 I	Ti O2	Titanium Oxide	Т	3.51	3.248800	1.687260	2.486230						
01-072-4816 I	Ti O2	Titanium Oxide	Т	3.52	3.248100	1.687030	2.486130						
01-072-4817 I	Ti O2	Titanium Oxide	Т	3.52	3.247810	1.686970	2.486190						
01-072-4818 I	Ti O2	Titanium Oxide	Т	3.53	3.247390	1.686930	2.486460						
01-072-4819 I	Ti O2	Titanium Oxide	Т	3.53	3.247110	1.686830	2.486390						
01-072-4820 I	Ti O2	Titanium Oxide	Т	3.53	3.247440	1.687010	2.486660						
01-072-4821 I	Ti O2	Titanium Oxide	Т	3.57	3.247370	1.687020	2.486740						
01-072-7058	Ti O2	Titanium Oxide	Т	4.88	3.518310	1.893350	2.378730						
01-072-7119 I	Ti O2	Titanium Oxide	A	18.43	12.932000	6.466000	4.310670						
01-072-7374 S	Ti O2	Titanium Oxide	Т	3.27	3.270860	2.505510	1.699460						
01-073-1764 I	Ti O2	Titanium Oxide	Т	4.89	3.508270	1.888000	2.371500						
01-073-1765 I	Ti O2	Titanium Oxide	Т	3.45	3.244910	2.483870	1.685430						
01-073-1774 I	(Ti O.716	Titanium Oxide	С	3.78	2.098300	2.422910	1.483720						
01-075-1537 I	Ti O2	Titanium Oxide	Т	5.2	3.474540	1.870000	2.347500						
01-075-1582	Ti O2	Titanium Oxide	0	1.62	3.510870	2.900010	3.464020						
01-076-1935 S	Ti O2	Titanium Oxide	0	1.62	3.512060	2.901400	3.467840						
01-076-1936 S	Ti O2	Titanium Oxide	0	1.63	3.516710	2.905450	3.472170						
01-076-1937 S	Ti O2	Titanium Oxide	0	1.61	3.523590	2.911840	3.479830						
01-076-1938 S	Ti O2	Titanium Oxide	Т	3.64	3.247740	1.687350	2.487480						
01-076-1939 S	Ti O2	Titanium Oxide	Т	3.55	3.254810	1.691130	2.493230						
01-076-1940 S	Ti O2	Titanium Oxide	Т	3.47	3.264000	1.696390	2.501830						
01-076-1941 S	Ti O2	Titanium Oxide	Т	3.44	3.268950	2.508280	1.699790						
01-079-1640 H	Ti O2	Titanium Oxide	Т	3.57	3.290170	1.703270	2.500480						
01-082-0514 H	Ti O2	Titanium Oxide	Т	3.43	3.187640	2.513030	1.677950						
01-083-2242 B	ТІ О2	Titanium Oxide	Т	4.14	3.245620	1.686790	2.487600						
Search Description													
{Empirical Formula Con	tains Elements '	Ti' And 'O2'} And {Nun	nber of E	lements (2)}									

TiO2's and I/Ic Displayed



Selecting Appropriate I/Ic Values

- <u>Choose the appropriate structure.</u>
 Many materials have polymorphs that have the same chemical formula, but different structures. These have different I/Ic's.
- <u>Match the reference to the specimen</u> as closely as possible.
- <u>Use quality marks and indicators</u> to select the best quality reference.



sitv

Selecting I/Ic - Structure



TiO2 Rutile I/Ic = 3.54





TiO2 Brookite I/Ic = 3.06



Formulae are the same, pattern, structure and I/Ic are distinctly different





TiO2 Anatase I/Ic = 5.04



OK.

Cancel

Structure

From Search Results use the Preferences Tab to select fields



Help General Search PDF Card Diffraction SIeve+ Electron Field Sets 🖕 Add... 🞽 Delete ICDD Defaults Rename... Available Fields Selected Fields Common Name OM Author Chemical Formula ~ Coden Mineral Name Journal Compound Name Title SYS CAS SG # Year I/Ic Pearson w/o H SPGR V AuthCell-a Prototype Structure AuthCell-b LPF Prototype Structure AuthCell-c Pearson Prompt for report title Scale report fields to page

Reset Page

Reset All

Apply.

You can select many fields that help you determine the structure by matching these data to the experimental data.

These include:

Chemical Name, Mineral Name

System and Space Group Number (SG#)

Pearson, Prototype Structure and LPF Prototype Structure

Reduced Cell, Author Cell and Crystal Cell

Strong Line (D1, D2, D3) and Long Line (L1, L2, L3)



Match Reference to Experiment





Temperature can expand or contract the unit cell – and change I/Ic.

All the known factors that can alter a structure: temperature, pressure, anion or cation substitution, synthesis conditions, vacancies, stress, strain, etc. will change atom positions, electron density distribution, and therefore alter peak intensities and the I/Ic ratio.

The above factors are changes in the **Kia factor** in the equation for quantitative analysis.

Select a reference that most closely matches your experiment!



Matching References

From the Results Form, select Preferences, add Database Comments	<u>×</u>	🔛 Preferences
From the Results Form, select Preferences, add Database Comments		Help
From the Results Form, elect Preferences, add Database Comments		General Search PDF Card Diffraction SIeve+ Electron
ICDD Defaults Add Rename Image: Comment and	A Distance in the local distance in the loca	Field Sets
Available Fields Selected Fields PDF # QM Chemical Formula I/Ic RedCell-0 RedCell-0 RedCell-10 RedCell-0 RedCell-10 RedCell-10 RedCell-10 RedCe		ICDD Defaults 🗸 🖓 Add Rename 💥 Delete
Prototype Structure Pot structure Line Line Database Comments Pot structure Line Prototype Structure		Available Fields
From the Results Form, RedCell-c RedCell-c RedCell.0 RedCell.0 RedCell.0 RedCell.0 RedCell.0 SPGR RedCell.0 RedCell.0 Pearson RedCell.0 SG # Image: Comments Interview Image: Comments Image: Comments Interview Image: Comments Image: Comments Interview Image: Comments Image: Comments		RedCell-a PDF #
rom the Results Form, elect Preferences, dd Database Comments		RedCell-b QM Chemical Formula
rom the Results Form, RedCell.β SPGR elect Preferences, RedCellVol SG # od Database Comments Prototype Structure I In Image: Comments Image: Comments	rom the Deculte Form	RedCell.a I/Ic
elect Preferences, dd Database Comments	rom the Results Form,	RedCell.β SPGR
elect Preterences, dd Database Comments	ala at Duafanan ana	RedCell.y Pearson
dd Database Comments	elect Preterences,	
dd Database Comments		Prototype Structure
	dd Database Comments	LPF Prototype Structure
		Prompt for report title
Scale report fields to page		Scale report fields to page
OK Cancel Reset Page Reset All Apply		OK Cancel Reset Page Reset All Apply

04-007-5987	Ρ	Ті О2	3.54	P42/mnm	tP6.00	LPF Collection Code: 1403121. Sample Preparation: STARTING MATERIALS:TiO2. Compound Preparation: heated at 1173-1273 K for several hours. Temperature of Data Collection: 298 K. Unit Cell Data Source: Powder Diffraction.
04-007-6246	В	Ті О2	1.82	C2/m	mC24.00	LPF Collection Code: 1403721. Polymorphism/Phase Transition: B. Temperature of Data Collection: 290 K. Significant Warning: Reported temperature factor: on non H atoms are outside the range 0.001 <u<0.1. and="" calculation.="" cell="" data<br="" factors="" ignored="" in="" reported="" temperature="" the="" u="0.012" unit="" used="" was="" were="">Source: Powder Diffraction.</u<0.1.>
04-007-6487	I	Ti O2	3.05	Pbnm	oP12.00	Color: colorless. LPF Collection Code: 1404320. Sample Preparation: STARTING MATERIALS:TiO2. Compound Preparation: heated at 1473 K. Temperature Factor: Reported Anisotropic temperature factors (in Beta) were converted to B. Temperature of Data Collection: 293 K. Minor Warning: LPF Editor Comment: unit for isotropic displacement parameters omitted, assumed to be "anstrom 2. Unit Cell Data Source: Single Crystal.
		1	1	1		

Editor comments contain information on specimen preparation, impurities, temperature of data collection and other factors that can change I/Ic. They can guide you to the appropriate choice.



I/Ic for Quartz Space Group P3221 75 Determinations





Using Quality Marks and Indicators

Preferences 🔀											
alp											
eneral Search PDF Card Diffraction SIeve+ Electron											
Field Sets ICDD Defaults											
Available Fields Selected Fields Ihemical Formula I/Ic Impirical Formula I/Ic NX SPGR Veight % QM Vtomic % Status t El's SS/FOM Compound Name Database Comments											
Tineral Name Nuthor Coden											
] Scale report fields to page											
OK Cancel Reset Page Reset All Apply											

The database contains many quality Indicators. These include:

Indicator Quality Mark Status SS/FOM R-Factor

<u>High Quality Value</u> S Primary Highest Number Lowest Number

Database Comments: This includes comments from editors and statistical analyses conducted on the data.

The indicators are defined in the Help documentation in the database.

Use "Preferences" to display quality marks and indicators.



Using Quality Marks and Indicators

Poor Quality

Low Quality Marks are designations B and O Low Quality Status would be a "Deleted" pattern R-factors >0.10 (i.e., 10%) and SS/FOM's below 10 are indications of poor quality

In general, any data meeting the above criteria should not be used in a quantitative analysis calculation as the ICDD's editorial analysis and review would indicate that the calculation may result in large errors.

The data are included because there may not be better alternative choices for a particular material or the entry may contain other types of unique data (i.e., measured physical properties, novel synthesis, etc.).



Using Cross References

What if a Search/Match program identified an entry with a poor quality mark or poor quality indicator?

- Check the Cross References



In this example, a Search/Match program identified entry PDF 04-08-7810, which has an I/Ic of 3.6 and a "B" Quality Mark. The editors' comments mention that the atomic parameters were derived (not experimentally determined or calculated) from the original publication. This results in low precision for the cell parameters and I/Ic values.

Solution: The entry contains crossreferences identified in the "Miscellaneous Tab" of the entry. The primary (high quality) entry is highlighted and is an active link in the database. The primary entry has an I/Ic of 3.61 and is an "S" quality entry.



Application Examples

- Using ICDD's Sleve and Sleve+ programs, materials are identified, peak intensities of each phase are calculated and I/Ic values are displayed – allowing the user to calculate concentrations by the RIR method.
- Many software distributors have RIR calculation modules, which can perform multiple, simultaneous calculations for complex mixtures, use integrated intensities and correct for absorption – all in a matter of seconds!

Examples are shown for the above.



Sleve+

Input experimental

													Πρυ	n expe	minemai	
GOM	PDF #	Compound Name 🔺	Chemical Formula	D1	D2	D3	D4	D5	D6	D7	D8		dote			
1254	04-007-6692	Cerium Titanium Oxide	Ce2 Ti2 O7	2.976300	2.982970	4.186270	3.215220	2.699360	2.757500	2.707670	2.777650 1		Jala	1.		
624	01-071-7093	Cerium Yttrium	(Ce0.98 Y0.02)	2.979130	2.580000	1.555800	1.824340	1.183790	1.153810	1.489560	0.872199 1					
862	04-006-7962	Cerium Zirconium Oxide	Ce0.15 Zr0.85 O2	2.983250	1.832240	1.551350	1.816240	2.568560	1.571400	2.614390	1.188360 1					
768	04-006-7961	Cerium Zirconium Oxide	Ce0.12 Zr0.88 O2	2.980390	1.830300	1.550080	1.814850	2.566590	1.569450	2.610850	1.187120 1					
580	04-006-7959	Cerium Zirconium Oxide	Ce0.1 Zr0.9 O2	2.978710	1.828770	1.549810	1.814800	2.566510	1.567310	2.606500	1.186180					
542	01-071-3203	Cesium Ammine Phosphide	(Cs3 P11) (NH3)3	2.989480	8.007960	3.130050	3.366560	4.097300	4.639240	4.156330	3.53 .00 1					
1223	04-009-5795	Cesium Antimony Iodide	C\$3 5b2 19	2.983960	3.440150	3.462000	2.105000	2.114990	5.967910	1.798620	7.795530 8			nhaaa	idantifia	
								J					IWC	phase		allon
Matches	Filter Filter	Description												· · · ·		
										1		1	n th	ie analy	vsis of ar	
Select.								-						io anai	yoio oi ai	•
Experiment						Lines (1	4 of 20)		1				ink	nown		
						- 1/21		1	8) [_		1/82	, c				
Search Line	(s): 2.98220	A D1 Range: 2.968 - 2	A Rotation:	1 01 3		Ex d(A)	EX I	P1 d(A) P	11 P2 (3(A) P21					
Preference	s					0.4421	94 Z	0.4007	90 100							
Search Win	dow: 0.15	• Mate	h Window: 0.15 °			5 1600	1 9	0.4307	00 100							
Course Mak	hadi line eneli		at Allawahla COM 500			4,9043	7 15	4.9041	60 18							
Searchined	nou, manawait	Lowe	SC Allowable GOH: 500			4.8598	1 8	4.8563	50 9							\mathbf{v}
Wavelengti	n: Cu Kat 1	.54056Ă				4.6690	4 11	4.6659	00 9							A.,
Phases (2)						4.08603	3 38	4.0833	00 38				a		· Cra	a
		DE # Company d Name		T- T		3.52993	3 6							_ =		_
# 🔺 Ac	cepted P		Inc. Ratio Inc. % I)	1C 11	me	3.43370) 6								/1/1 \	V
2	01-0	89-1487 Magnesium Aluminum Silicate	1.11 78 1.41	47.5S		3.38019	9 27	3.3803	80 26							X.
	040	centan zirconian oxide	0.311 22 10.00	00.35		3.3427	1 5	0.1464	00.14				b		C/D	D
						3,1491	2 13	3,1404	40 25				~			
			4			3.0937	1 4	3.1250	10 33							
						3.0318	4 39	3.0295	00 26							
						3.0117	3 40	3.0106	20 23				4			
	$ R \rho$		anv			2.98220) 29			2,983	3250 100					
						2.6435	4 11	2.6406	70 11							
			_ \			2,33576	5 5	2,3329	50 7							
						1.83616	5 12	1.8380	80 1	1.832	240 32					
						<u> </u>										
													1.1			
			C	ompo	und M	Jame	•			Int.	Ratio	Int. 9	%	I/Ic		
			Magnesium A	luminu	um Si	licate	8		·	1.11		78	1	.41		
			Cerium Zircor	nium C	Dxide				<u> </u>	0.311		22	1	0.88		

This results in 96% magnesium aluminum silicate and 4% cerium zirconium oxide and uses peak intensities.



Automated RIR Analysis Vendor Software – Same Example



This software calculated 92% magnesium aluminum silicate and 7% cerium zirconium oxide using integrated intensities.



Thank you for viewing our tutorial. Additional tutorials are available at the ICDD website (www.icdd.com).

International Centre for Diffraction Data 12 Campus Boulevard Newtown Square, PA 19073 Phone: 610.325.9814 Fax: 610.325.9823